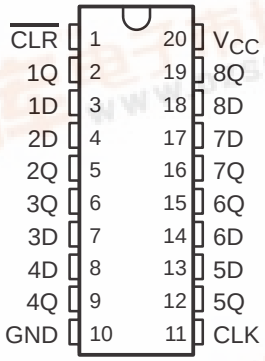
SN54HCT273, SN74HCT273
OCTAL D-TYPE FLIP-FLOPS WITH CLEAR

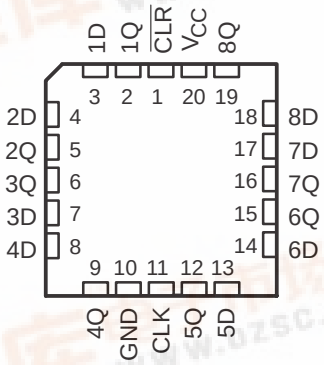
SCLS068C – NOVEMBER 1988 – REVISED MAY 1997

- **Inputs Are TTL-Voltage Compatible**
- **Contain Eight D-Type Flip-Flops**
- **Direct Clear Input**
- **Applications Include:**
  - **Buffer/Storage Registers**
  - **Shift Registers**
  - **Pattern Generators**
- **Package Options Include Plastic Small-Outline (DW) and Ceramic Flat (W) Packages, Ceramic Chip Carriers (FK), and Standard Plastic (N) and Ceramic (J) 300-mil DIPs**

SN54HCT273 . . . J OR W PACKAGE
SN74HCT273 . . . DW, N, OR PW PACKAGE
(TOP VIEW)



SN54HCT273 . . . FK PACKAGE
(TOP VIEW)



description

These devices are positive-edge-triggered D-type flip-flops with a common enable input. The 'HCT273 are similar to the 'HCT377, but feature a common clear enable ($\overline{CLR}$) input instead of a latched clock.

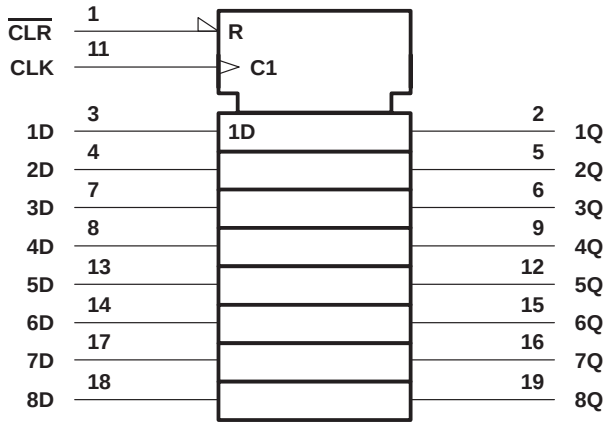
Information at the data (D) inputs meeting the setup time requirements is transferred to the Q outputs on the positive-going edge of the clock (CLK) pulse. Clock triggering occurs at a particular voltage level and is not directly related to the positive-going pulse. When CLK is at either the high or low level, the D input has no effect at the output. The circuits are designed to prevent false clocking by transitions at $\overline{CLR}$.

The SN54HCT273 is characterized for operation over the full military temperature range of –55°C to 125°C. The SN74HCT273 is characterized for operation from –40°C to 85°C.

FUNCTION TABLE
(each flip-flop)

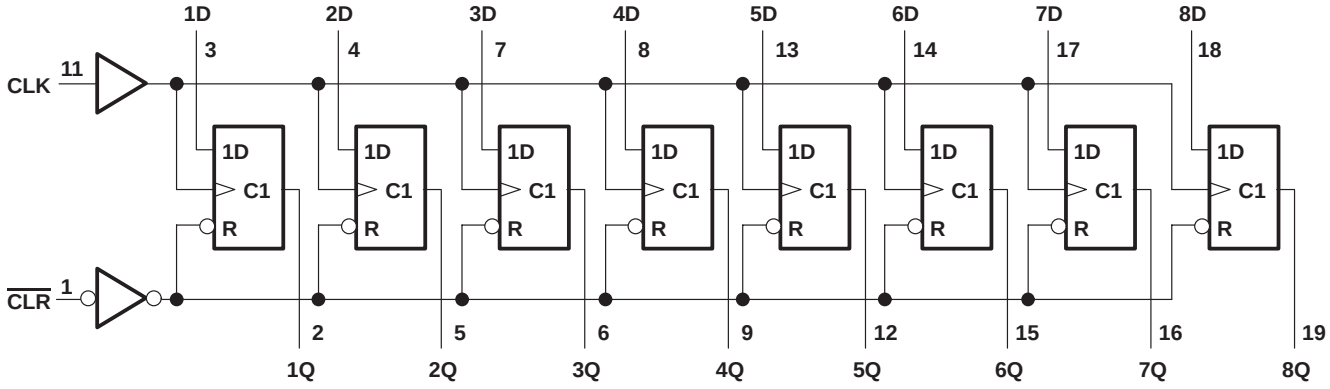
INPUTS			OUTPUT
$\overline{CLR}$	CLK	D	Q
L	X	X	L
H	↑	H	H
H	↑	L	L
H	L	X	Q_0

logic symbol†

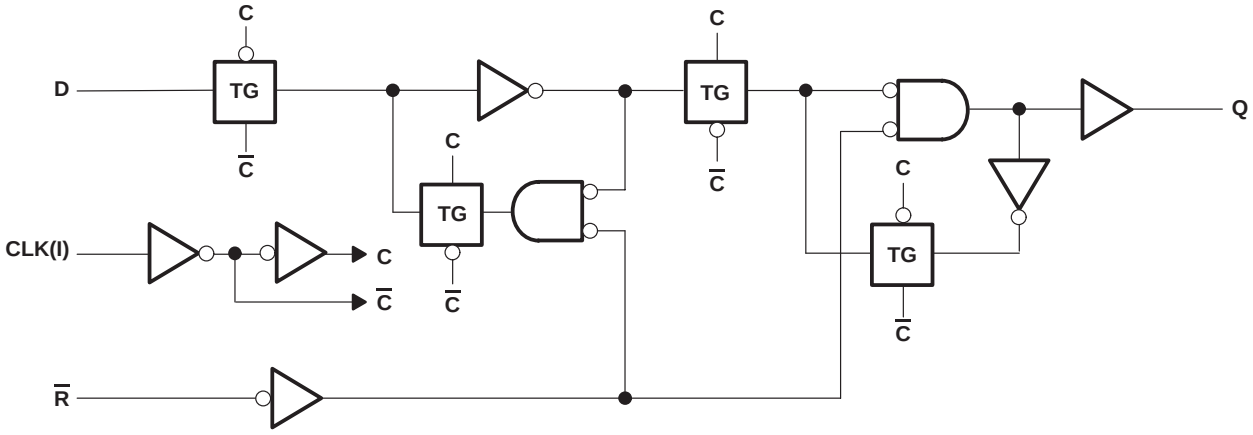


† This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

logic diagram (positive logic)



logic diagram, each flip-flop (positive logic)



absolute maximum ratings over operating free-air temperature range†

Supply voltage range, V_{CC} . . . . . –0.5 V to 7 V
Input clamp current, I_{IK} ($V_I < 0$ or $V_I > V_{CC}$) (see Note 1) . . . . . ±20 mA
Output clamp current, I_{OK} ($V_O < 0$ or $V_O > V_{CC}$) (see Note 1) . . . . . ±20 mA
Continuous output current, I_O ($V_O = 0$ to V_{CC}) . . . . . ±25 mA
Continuous current through V_{CC} or GND . . . . . ±50 mA
Package thermal impedance, θ_{JA} (see Note 2): DW package . . . . . 97°C/W
N package . . . . . 67°C/W
PW package . . . . . 128°C/W
Storage temperature range, T_{stg} . . . . . –65°C to 150°C

† Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTES: 1. The input and output voltage ratings may be exceeded if the input and output current ratings are observed.
2. The package thermal impedance is calculated in accordance with JESD 51, except for through-hole packages, which use a trace length of zero.

recommended operating conditions

			SN54HCT273			SN74HCT273			UNIT
			MIN	NOM	MAX	MIN	NOM	MAX	
V_{CC}	Supply voltage		4.5	5	5.5	4.5	5	5.5	V
V_{IH}	High-level input voltage	V_{CC} = 4.5 V to 5.5 V	2			2			V
V_{IL}	Low-level input voltage	V_{CC} = 4.5 V to 5.5 V	0		0.8	0		0.8	V
V_I	Input voltage		0		V_{CC}	0		V_{CC}	V
V_O	Output voltage		0		V_{CC}	0		V_{CC}	V
t_t	Input transition (rise and fall) times		0		500	0		500	ns
T_A	Operating free-air temperature		–55		125	–40		85	°C

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS		V_{CC}	T_A = 25°C			SN54HCT273		SN74HCT273		UNIT
				MIN	TYP	MAX	MIN	MAX	MIN	MAX	
V_{OH}	$V_I = V_{IH}$ or V_{IL}	I_{OH} = –20 µA	4.5 V	4.4	4.499		4.4		4.4		V
		I_{OH} = –4 mA	4.5 V	3.98	4.30		3.7		3.84		
V_{OL}	$V_I = V_{IH}$ or V_{IL}	I_{OL} = 20 µA	4.5 V		0.001	0.1		0.1		0.1	V
		I_{OL} = 4 mA	4.5 V		0.17	0.26		0.4		0.33	
I_I	$V_I = V_{CC}$ or 0		5.5 V			±0.1	±100		±1000		±1000	nA
I_{CC}	$V_I = V_{CC}$ or 0, I_O = 0		5.5 V			8		160		80	µA
ΔI_{CC}‡	One input at 0.5 V or 2.4 V, Other inputs at 0 or V_{CC}		5.5 V		1.4	2.4		3		2.9	mA
C_i			4.5 V to 5.5 V		3	10		10		10	pF

‡ This is the increase in supply current for each input that is at one of the specified TTL voltage levels rather than 0 V or V_{CC}.

timing requirements over recommended operating free-air temperature range (unless otherwise noted)

			V_{CC}	T_A = 25°C		SN54HCT273		SN74HCT273		UNIT
				MIN	MAX	MIN	MAX	MIN	MAX	
f_{clock}	Clock frequency		4.5 V	0	25	0	16	0	20	MHz
			5.5 V	0	28	0	19	0	23	
t_w	Pulse duration	CLK high or low	4.5 V	20		30		25		ns
			5.5 V	18		25		22		
		$\overline{CLR}$ low	4.5 V	16		24		20		
			5.5 V	14		20		17		
t_{su}	Setup time before CLK↑	Data	4.5 V	20		30		25		ns
			5.5 V	17		25		21		
		$\overline{CLR}$ inactive	4.5 V	20		30		25		
			5.5 V	17		25		21		
t_h	Hold time data after CLK↑		4.5 V	0		0		0		ns
			5.5 V	0		0		0		

switching characteristics over recommended operating free-air temperature range, V_{CC} = 5 V ± 0.5 V, C_L = 50 pF (unless otherwise noted) (see Figure 1)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	V_{CC}	SN54HCT273				UNIT
				T_A = 25°C			MIN	MAX	
				MIN	TYP	MAX			
f_{max}			4.5 V	25	31		16		MHz
			5.5 V	28	37		19		
t_{pd}	$\overline{CLR}$	Any	4.5 V		15	34		50	ns
			5.5 V		12	29		42	
t_{PHL}	$\overline{CLR}$	Any	4.5 V		17	15		50	ns
			5.5 V		15	34		42	
t_t		Any	4.5 V		8	18		22	ns
			5.5 V		7	19		21	

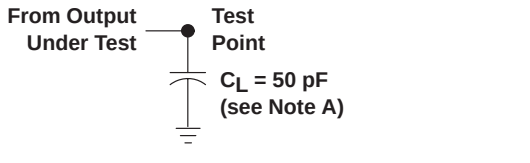
switching characteristics over recommended operating free-air temperature range, V_{CC} = 5 V ± 0.5 V, C_L = 50 pF (unless otherwise noted) (see Figure 1)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	V_{CC}	SN74HCT273				UNIT
				T_A = 25°C			MIN	MAX	
				MIN	TYP	MAX			
f_{max}			4.5 V	25	31		20		MHz
			5.5 V	28	37		23		
t_{pd}	$\overline{CLR}$	Any	4.5 V		15	34		42	ns
			5.5 V		12	29		36	
t_{PHL}	$\overline{CLR}$	Any	4.5 V		17	34		42	ns
			5.5 V		15	29		36	
t_t		Any	4.5 V		8	15		19	ns
			5.5 V		7	14		17	

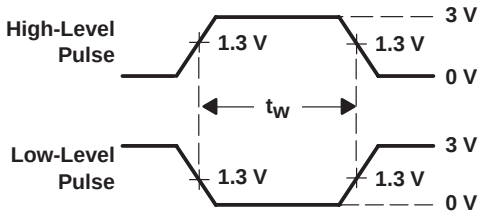
operating characteristics, V_{CC} = 5 V, T_A = 25°C

PARAMETER		TEST CONDITIONS	TYP	UNIT
C_{pd}	Power dissipation capacitance	No load	30	pF

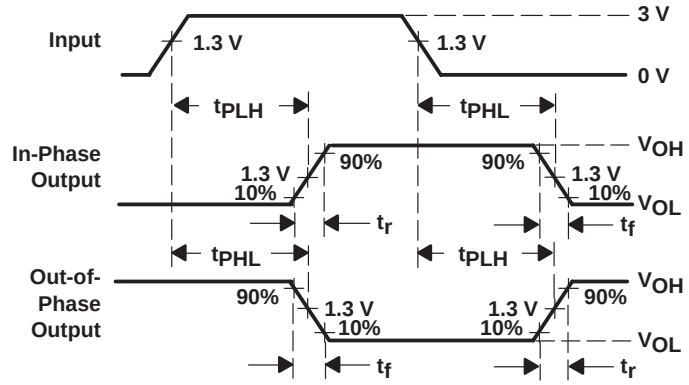
PARAMETER MEASUREMENT INFORMATION



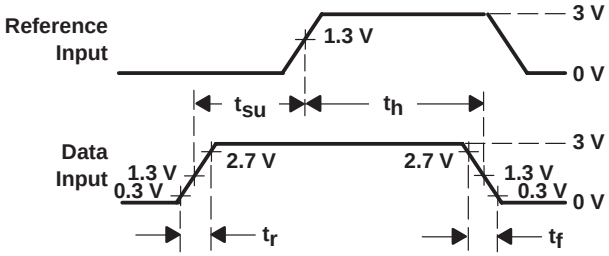
LOAD CIRCUIT



VOLTAGE WAVEFORMS
PULSE DURATIONS



VOLTAGE WAVEFORMS
SETUP AND HOLD AND INPUT RISE AND FALL TIMES



VOLTAGE WAVEFORMS
PROPAGATION DELAY AND OUTPUT RISE AND FALL TIMES

NOTES: A. C_L includes probe and test-fixture capacitance.
B. Phase relationships between waveforms were chosen arbitrarily. All input pulses are supplied by generators having the following characteristics: PRR ≤ 1 MHz, Z_O = 50 Ω, t_r = 6 ns, t_f = 6 ns.
C. The outputs are measured one at a time with one input transition per measurement.
D. For clock inputs, f_{max} is measured when the input duty cycle is 50%.
E. t_{PLH} and t_{PHL} are the same as t_{pd}.

Figure 1. Load Circuit and Voltage Waveforms

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